

Search Notes**Application/Control No.**

10/697,906

Examiner

Eric D. Bertram

Applicant(s)/Patent under Reexamination

CHIN ET AL.

Art Unit

3762

SEARCHED

| Class | Subclass | Date | Examiner |
|-------------------------------------|----------|-----------|----------|
| 607 | 17 | 9/27/2005 | EDB |
| | 18 | 9/27/2005 | EDB |
| | 119 | 9/27/2005 | EDB |
| | 127 | 9/28/2005 | EDB |
| | 129 | 9/28/2005 | EDB |
| | 130 | 9/28/2005 | EDB |
| <i>same as above up to date</i> | | 3/20/06 | EDB |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|----------------------------------|-----------|------|
| EAST notes, see attached | 9/29/05 | EDB |
| Inventor search on eDAN and PALM | 9/26/2005 | EDB |
| Consulted with Carl Layno (3762) | 10/3/2005 | EDB |
| Consulted with Mark Bockelman | 3/21/2006 | EDB |
| | | |
| | | |
| | | |
| | | |

INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |